

U.S. Application No. 09/976,579
Amtd. dated October 8, 2003
Reply to Office Action of July 8, 2003



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Sundar Amartur

Application No.: 09/976,579

Confirmation No.: 2460

Filed: October 12, 2001

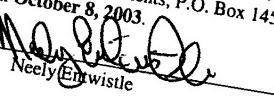
For: IN-SITU DETECTION OF THIN-METAL
INTERFACE USING HIGH RESOLUTION
SPECTRAL ANALYSIS OF OPTICAL
INTERFERENCE

) Group Art Unit: 2877
Examiner: Geisel, Kara E
Atty. Docket No: LAM2P253.CIP2
Date: October 8, 2003

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the
United States Postal Service as First Class Mail in an envelope
addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria,
VA 22313-1450 on October 8, 2003.

Signed: _____


Neely Enwistle

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OCT 21 2003

TECHNOLOGY CENTER 2803

Dear Sir:

AMENDMENT

Applicant submits this paper in response to the Office Action mailed July 8, 2003.
Please amend this application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the claims are reflected in the listing of claims which begins on page
3 of this paper.

Remarks/Arguments begin on page 7 of this paper.

Amendment